

## Supporting Information

# High-Efficiency and Durable Inverted Perovskite Solar Cells with Thermally-Induced Phase-Change Electron Extraction Layer

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## Experimental Section

**Materials.** All the commercial materials were used as received. Lead iodide ( $\text{PbI}_2$ ) and lead bromide ( $\text{PbBr}_2$ ) was purchased from TCI. *N*, *N*-dimethylformamide (DMF), dimethylsulfoxide (DMSO), chlorobenzene (CB), toluene, and isopropanol (IPA) were purchased from Sigma-Aldrich. Formamidinium iodide (FAI) and methylammonium bromide (MABr) were purchased from GreatCell Solar (Australia). Phenyl-C61-butyric acid methyl ester (PC<sub>61</sub>BM), poly[bis(4-phenyl) (2,4,6-trimethylphenyl) amine] (PTAA), cesium iodide (CsI), and bathocuproine (BCP) were purchased from Xi'an Polymer Light Technology Co., Ltd. Vanadium dioxide ( $\text{VO}_2$ ) nanoparticles were directly purchased from Jingcheng Chemicals Co., Ltd, China or were prepared according to other published work. ITO-coated glasses were purchased from Yingkou You Xuan Trade Co., Ltd. Other chemicals were purchased from Aladdin.

**VO<sub>2</sub> dispersed solution.** The 25 mg  $\text{VO}_2$  nanoparticles were first dispersed in 5 ml ethanol. In order to obtain continuous  $\text{VO}_2$  films, the dispersant (that is Si-Al gel), was mixed with  $\text{VO}_2$  in ethanol with volume ratio of 1: 1. The preparation method of Si-Al gel was reported by us previously [*J. Colloid. Interface. Sci.*, 2014, 427:

49-53]. The as-prepared  $\text{VO}_2$  solution was then stirred for 2 h and stored for use without further processing.

**Device Fabrication.** The ITO glass substrates were sequentially cleaned by ultrasonication with detergent, deionized water, acetone and IPA for 15 min, respectively. The cleaned ITO substrates were transferred into an oven at 100°C for drying and treated with  $\text{O}_2$  plasma for 15 min before use. Then, the hole transport layer, that is 10 mg ml<sup>-1</sup> PTAA in toluene, was spin-coated onto the ITO glass substrate at 4000 rpm for 30 s and this was subsequently annealed at 150°C for 10 min. For the fabrication of perovskite films, a typical one-step anti-solvent deposition method was obtained in this work. 1.4 M perovskite precursor solutions were prepared by mixing FAI,  $\text{PbI}_2$ ,  $\text{MABr}$ ,  $\text{PbBr}_2$  and  $\text{CsI}$  in DMF: DMSO mixed solvent (4:1/v:v) with a chemical formula of  $\text{Cs}_{0.05}(\text{FA}_{0.92}\text{MA}_{0.08})_{0.95}\text{Pb}(\text{I}_{0.92}\text{Br}_{0.08})_3$ . The perovskite precursor solution was spin-coated at 2000 rpm for 10 s and 4000 rpm for 50 s onto the PTAA coated ITO substrate, 150  $\mu\text{L}$  CB as anti-solvent was dripped on the film at 10 s before the end of the last procedure and then annealed at 100°C for 30 min. Subsequently, the devices were successively spin-coated with  $\text{PC}_{61}\text{BM}$  (20 mg ml<sup>-1</sup> in CB) at the rate of 1500 rpm for 45 s, annealed at 90°C for 10 min. An ultra-thin (5 nm) BCP was

deposited on the PC<sub>61</sub>BM surface by thermal evaporation to form a remarkable Ohmic contact to suppress the charge accumulation at the interface of ETL/metal electrodes. For the electron extraction layer, the VO<sub>2</sub> as-dispersed solution was spin-coated on the above PC<sub>61</sub>BM electron transport layer at different spin rate. Finally, 100 nm thick Ag was thermally evaporated on top through a shadow mask. The device active area was measured to 0.12 cm<sup>2</sup>.

**Computational Methods.** Density function theory (DFT) calculations were performed using the Vienna Ab initio Simulation Package (VASP 5.4.1) [*1. J. Comput. Chem.*, 2008, 29, 2044– 2078]. The projector augmented wave (PAW) method with the Perdew–Burke–Ernzerhof (PBE) exchange-correlation functional was used [*2. Phys. Rev. B*, 1994, 50 (24), 17953-17979; *3. Phys. Rev. Lett.*, 1996, 77, 3865–3868]. Plane-wave cutoff energy of 400 eV and energy convergence criterion of 10-8 eV was adopted for the self-consistent cycle throughout calculations. During the structural relaxation, 5×6×5 and 6×6×9 Monkhorst-Pack k-point meshes were employed for monoclinic VO<sub>2</sub> and rutile VO<sub>2</sub>, respectively. For accurate calculations of the electronic properties, we adopted the DFT+U at the same theory level with a more dense k-mesh of 10×11×10 and 11×11×18 for the monoclinic VO<sub>2</sub> and rutile VO<sub>2</sub>,

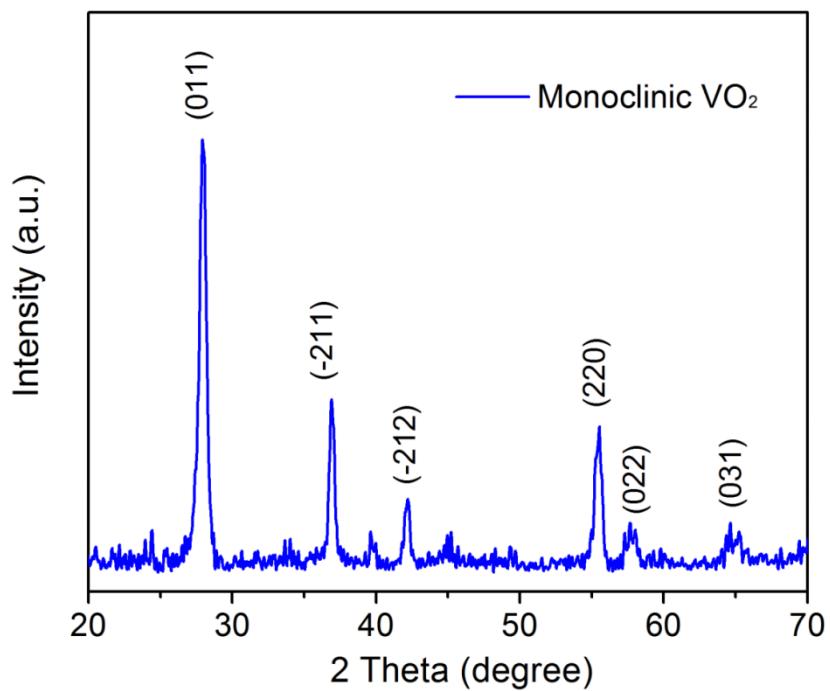
respectively. The Coulomb interaction parameter (U) and exchange interaction parameter (J) for the 3d atomic orbital of V were set to 2.8 and 0.93 eV, respectively [4. *Phys. Rev. Lett.*, 1999, 83(20), 4136-4139].

**Characterization.** The surface morphologies and microstructures of the perovskite and VO<sub>2</sub> films and the cross-sectional of perovskite devices were investigated by a field emission scanning electron microscopy (SEM, GeminiSEM300, Carl Zeiss) equipped with an energy-dispersive X-ray spectrometer (EDS). The VO<sub>2</sub> films were scraped, dispersed in ethanol, and then observed by transmission electron microscopy (TEM, JEM-2100, JEOL Ltd). X-ray photoelectron spectroscopy (XPS) measurement was carried out by a AXIS-ULTRA DLD-600W surface-analysis system equipped with a monochromatic Al K $\alpha$  X-ray source (1486.6 eV). Ultraviolet photoelectron spectroscopy (UPS) was measured using the XPS equipment, under irradiation with a He discharge lamp having the emission energy of 21.22 eV. Temperature-dependent crystal phases were conducted under different temperatures ranging from 25 to 105 °C during heating process by using X-ray diffraction (XRD, D8 Advance, Bruker) with Cu K $\alpha$  irradiation,  $\lambda=1.5406$  Å. UV-vis-NIR absorption and transmission spectrum of VO<sub>2</sub> films were recorded

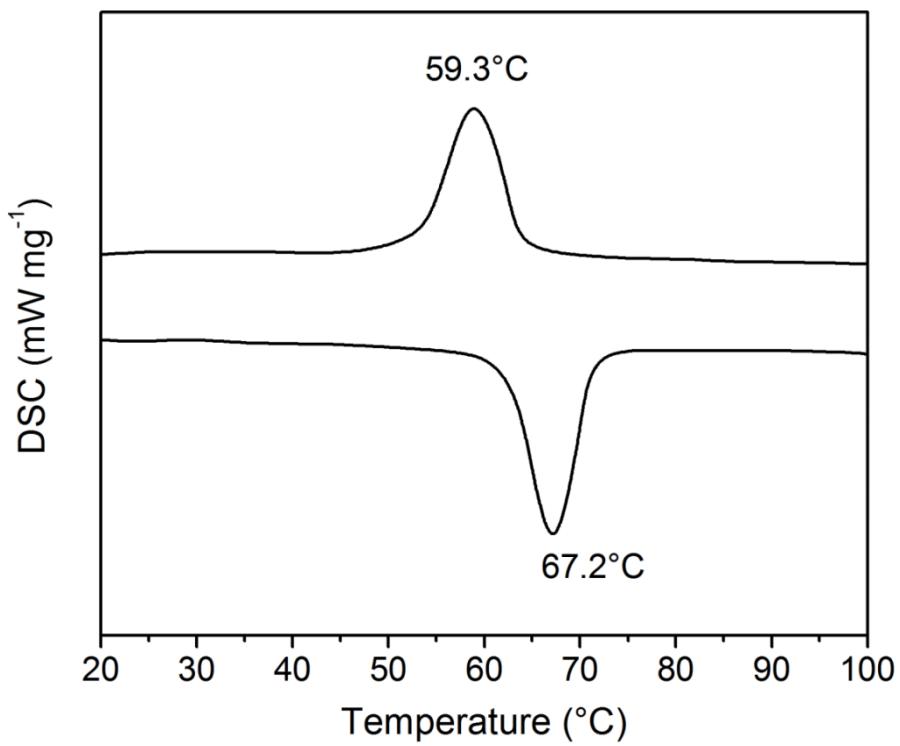
by the UV-vis-NIR spectrophotometry (Lambda 950, PerkinElmer), equipped with a 150 mm integrating spheres for signal collection. The spectrophotometries were integrated with an accessory containing a customized heating and cooling stage and a digital controller (PE120, Linkam) for temperature-dependent measurement. Temperature dependent Raman spectrum analysis in the range of 100-1000 cm<sup>-1</sup> wavenumber was done with a Renishaw inVia Raman microscope using 10% powered 514 nm laser. The work functions of the samples were investigated using ambient pressure photoemission spectroscopy with nitrogen environment (APS04-N2-RH, KP Technology Ltd). The steady-state photoluminescence (PL, excitation at 325 nm) and time-resolved photoluminescence (TRPL, excitation at 325 nm and emission at 760 nm) spectra were obtained using a lase spectrometer (FLS 980, Edinburgh Instruments Ltd). Electrochemical impedance spectroscopy (EIS) was measured by using a potentiostat (IviumStat 10800, Ivium Technologies) in a dark condition and a frequency range from 1MHz to 100 mHz. The transient photocurrent (TPC) decay and transient photovoltage (TPV) decay were recorded by electrochemical workstation (IviumStat 10800, Ivium Technologies) with a white light LED supplied 100 mW cm<sup>-2</sup> light intensity to excite the perovskite solar cells. The current-voltage (*J-V*) characteristics of the devices were measured in

a nitrogen glove box by a Keithley 2400 Source Meter under standard AM 1.5G illumination with a xenon-lamp-base solar simulator (Enlitech, SS-F5-3A). For the temperature-dependent  $J$ - $V$  curves, it were recorded from 25°C up to 85°C in steps of 10°C or 20°C under 1 Sun illumination. All temperature-dependent measurements were first taken in the N<sub>2</sub>-glove box at room temperature (25°C), then to the highest temperature (85°C) and finally back at room temperature (25°C) and the devices were not encapsulated. Our  $J$ - $V$  measurement system has been designed to be measured at different elevated temperature, which is integrated a small temperature-controlled heating table. So, the temperature can be tuned by the system software and this heating table. For contacting, a thermally coupled copper sample holder was used, placed on this temperature-controlled table and the thermocouple was attached the device's glass surface. Then device was in direct contact with the holder and reached the desired set temperature within a few minutes, as confirmed by the stabilized power output. Please note that the device should be waited about 10 mins for the MPP to stabilize the PCE output at the desired set temperature and then it can be measured for the  $J$ - $V$  curves. During device heating between different temperatures, the device was always kept under 1 Sun illumination. Both forward scan (from -0.2 to 1.2 V) and reverse

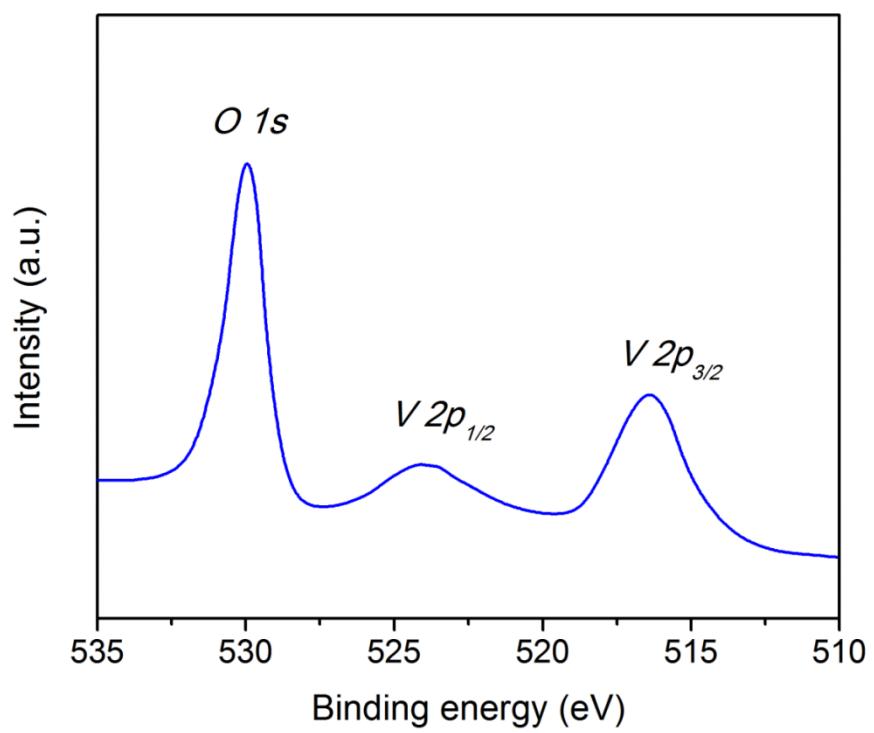
scan (from 1.2 to -0.2 V) were performed with a delay time of 100 ms. An AR MgF<sub>2</sub> film is deposited on the incident side of ITO-coated glass substrate. The intensity of the light was calibrated with a KG-5 filter Si diode. The incident photon-to-electron conversion efficiency (IPCE) spectra were measured with a QE-R3011 IPCE system (Enli Technology Co., Ltd) ranging from 300 to 850 nm. The device thermal stability tests were also carried out in a nitrogen glove box, and the devices were put on a hotplate with a temperature of 85°C.



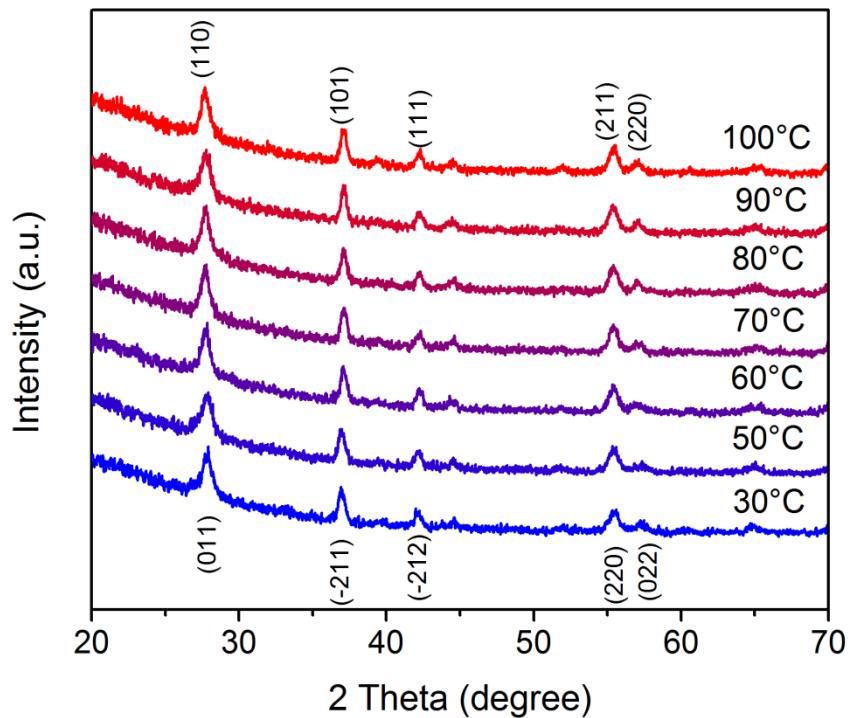
**Figure S1.** The XRD pattern of as-prepared VO<sub>2</sub> nanoparticles.



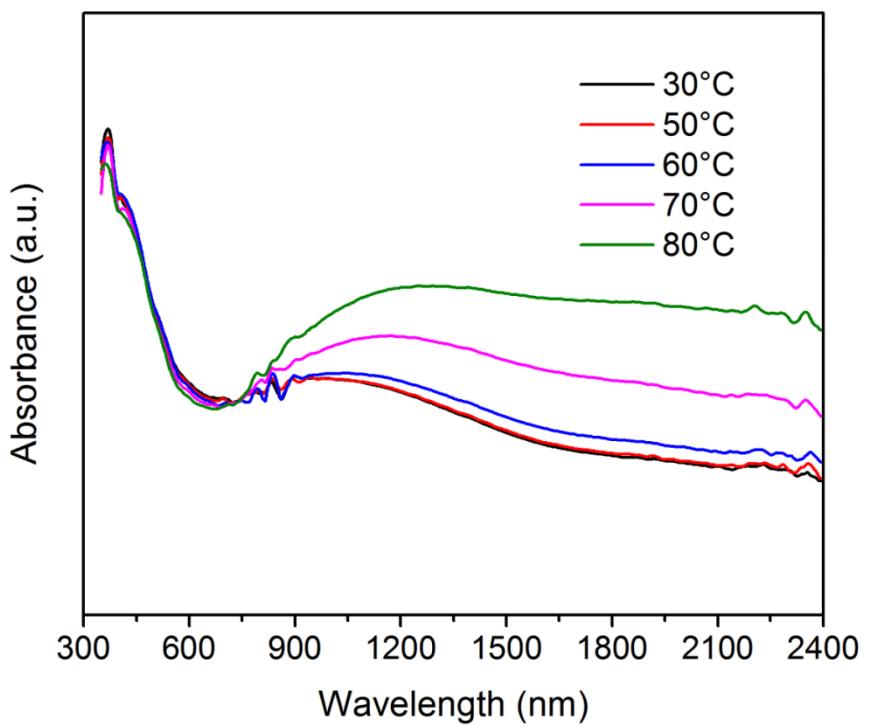
**Figure S2.** The DSC curves of the obtained VO<sub>2</sub> nanoparticles.



**Figure S3.** High-resolution XPS spectrum of as-prepared  $\text{VO}_2$  film.



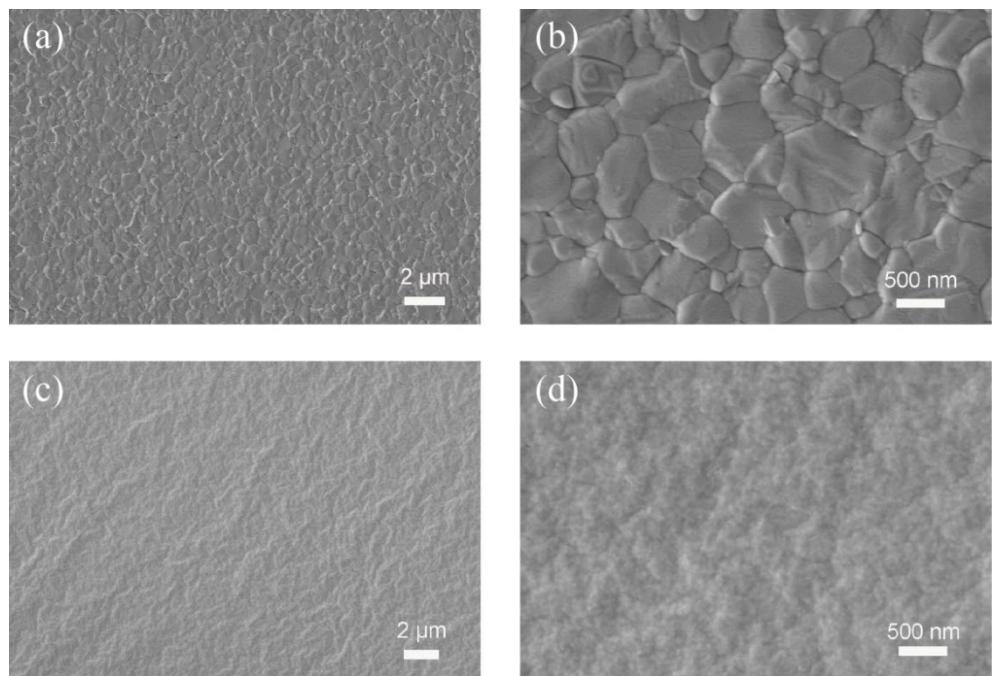
**Figure S4.** XRD patterns of VO<sub>2</sub> film (M/R) at temperature from 30 to 100°C. Note that the XRD pattern of VO<sub>2</sub> below 70°C has the same peak as shown in Figure S1.



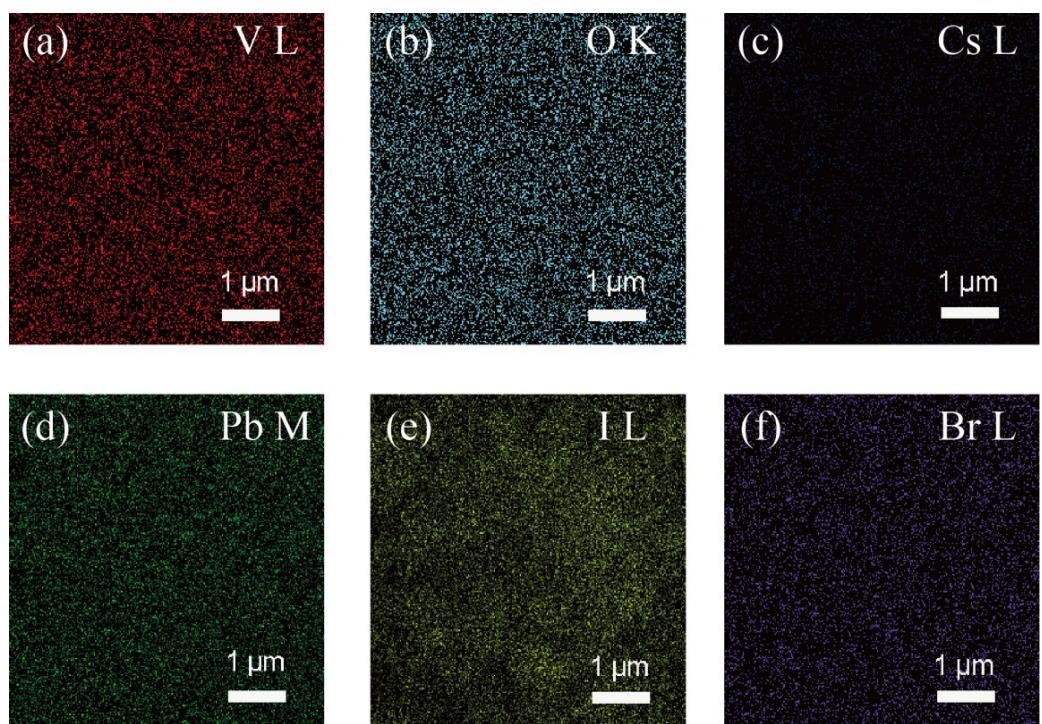
**Figure S5.** Temperature-dependent absorbance spectra of  $\text{VO}_2$  film.



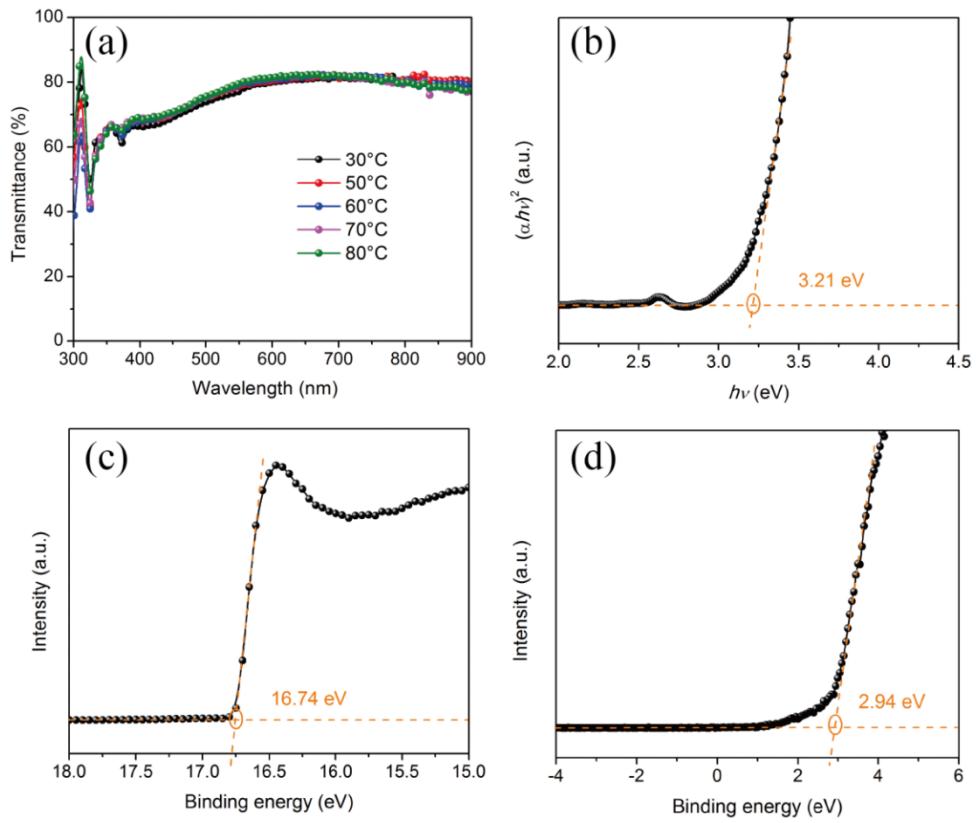
**Figure S6.** Photographs of the pure perovskite film (left) and the perovskite film covered by  $\text{VO}_2$  layer (right) on PTAA-coated ITO substrates.



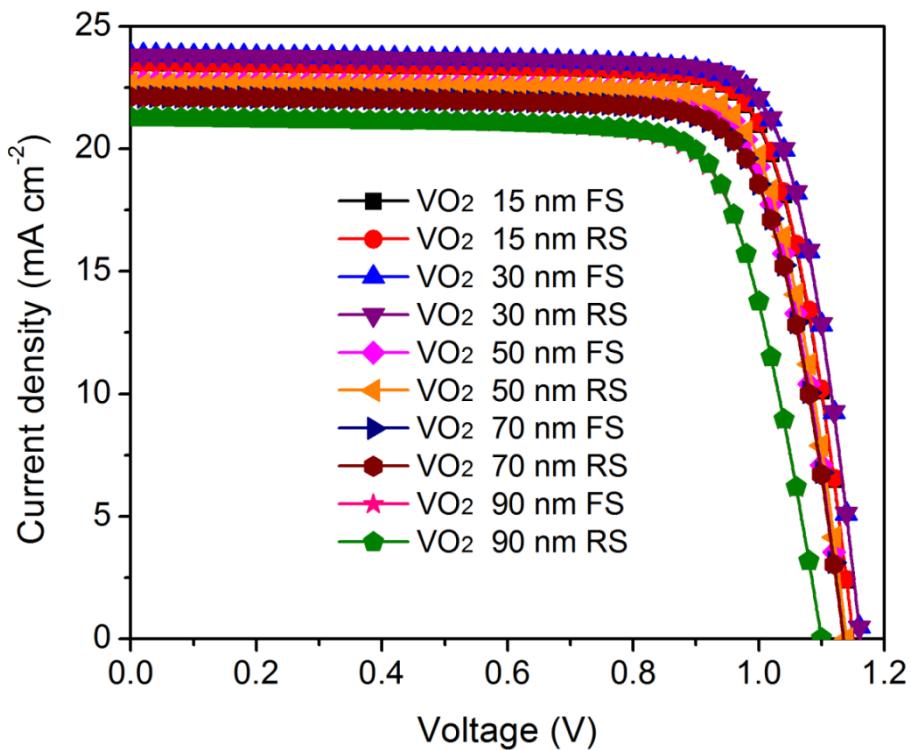
**Figure S7.** (a) SEM image of the perovskite film on the as-prepared PTAA/ITO substrate. (b) Corresponding magnified SEM image of the perovskite film on the PTAA/ITO substrate. (c) SEM image of as-deposited  $\text{VO}_2$  film on the as-prepared perovskite/PTAA/ITO substrate. (d) Corresponding magnified SEM image of  $\text{VO}_2$  film on the perovskite/PTAA/ITO substrate.



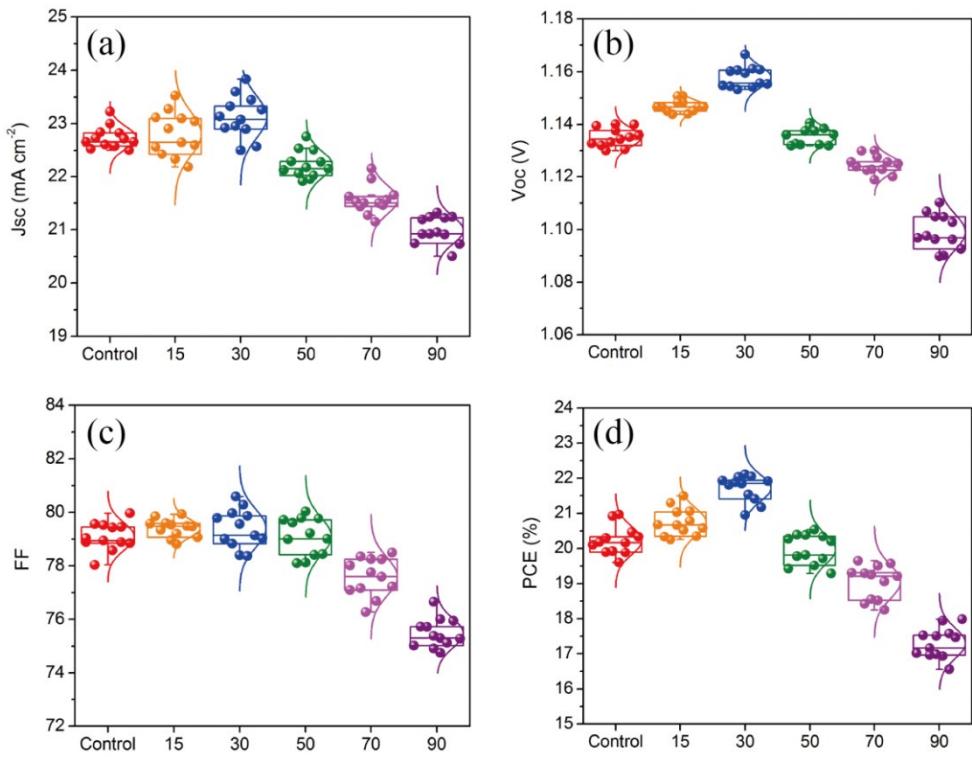
**Figure S8.** EDS mapping of V, O, Cs, Pb, I, and Br elements for the perovskite film covered by  $\text{VO}_2$  layer, respectively.



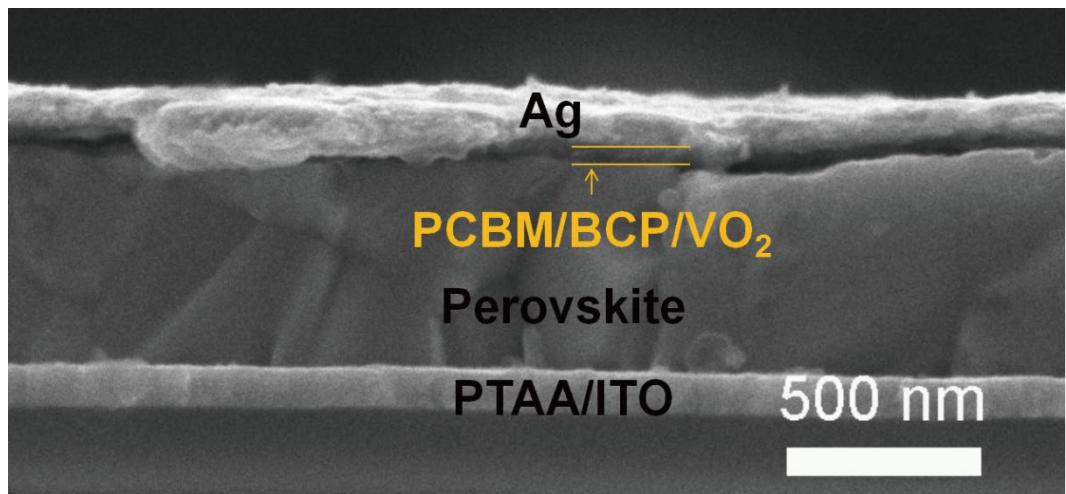
**Figure S9.** (a) Transmittance spectra of as-deposited  $\text{VO}_2$  film on ITO substrate. (b) The extrapolated plots of  $(\alpha h\nu)^2$  against  $h\nu$  obtained from the transmittance spectra of  $\text{VO}_2$  film. The calculated optical bandgap of  $\text{VO}_2$  is 3.21 eV. (c) The Fermi energy level of  $\text{VO}_2$  obtained from UPS is 4.48 eV. (d)  $E_f - E_v$  of  $\text{VO}_2$  is 2.94 eV. The calculated conduction band minimum for  $\text{VO}_2$  is 4.21 eV.



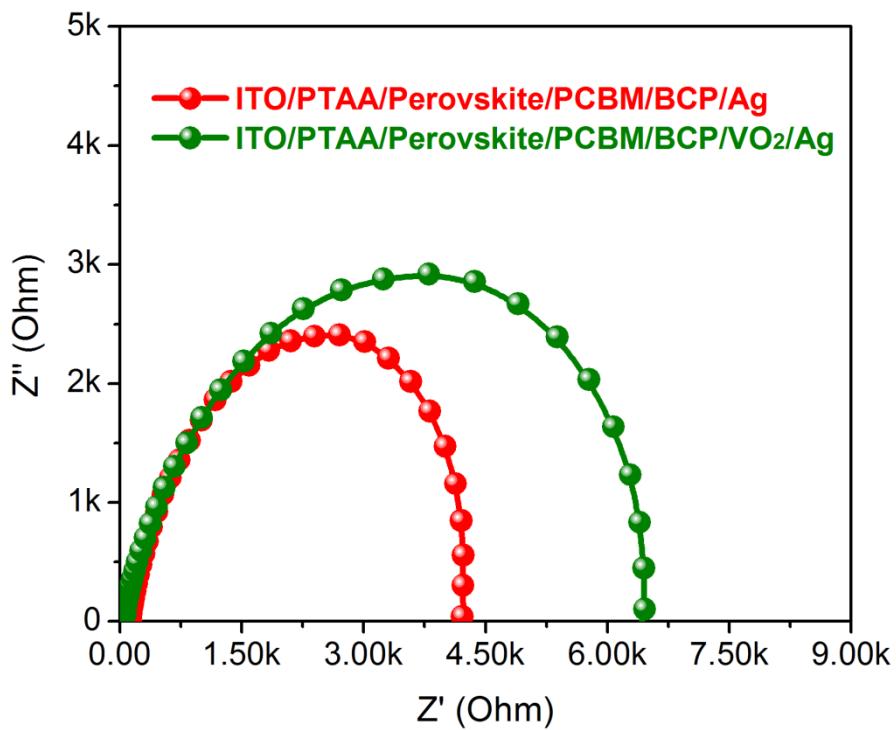
**Figure S10.** *J-V* curves of the devices based on different thicknesses of VO<sub>2</sub> layers under forward scan (FS) and reverse scan (RS).



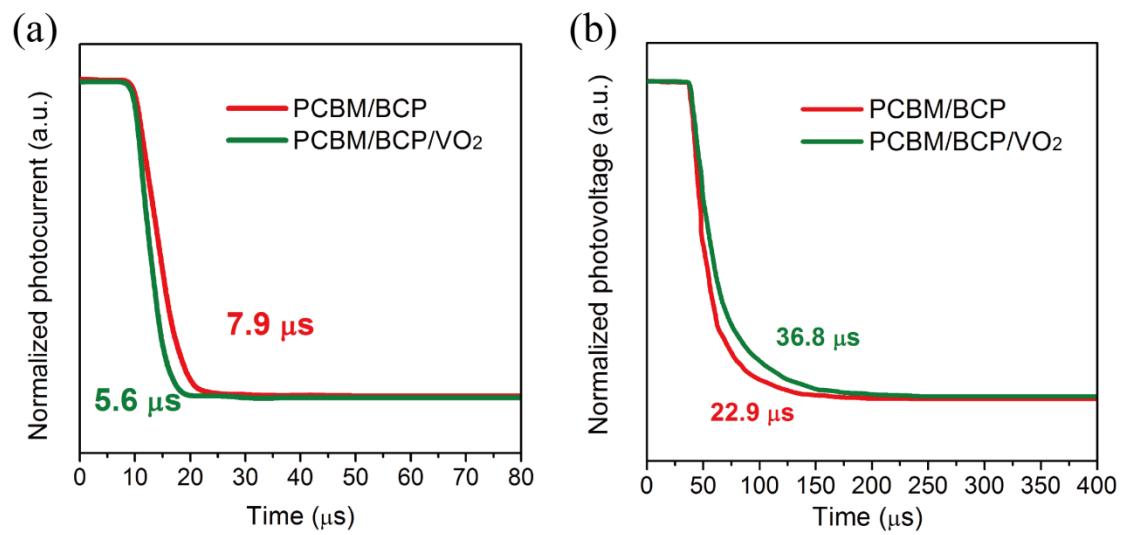
**Figure S11.** Box chart of photovoltaic parameters comparison of perovskite solar cells based on  $\text{VO}_2$  with various thickness. The data were statistically analyzed from 12 cells per sample type (thickness). (a)  $J_{\text{sc}}$  ( $\text{mA cm}^{-2}$ ), (b)  $V_{\text{oc}}$  (V), (c)  $FF$ , (d) PCE (%).



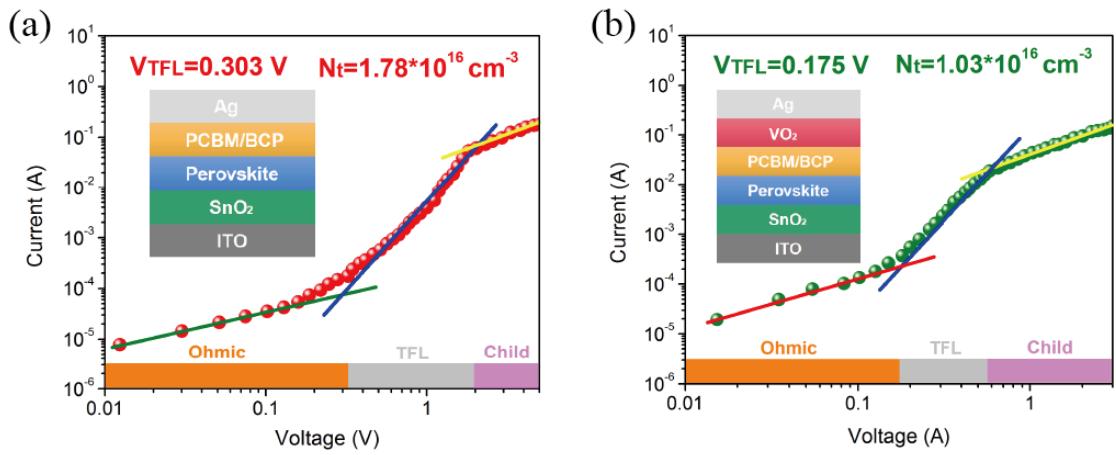
**Figure S12.** Cross-sectional SEM images of the studied device.



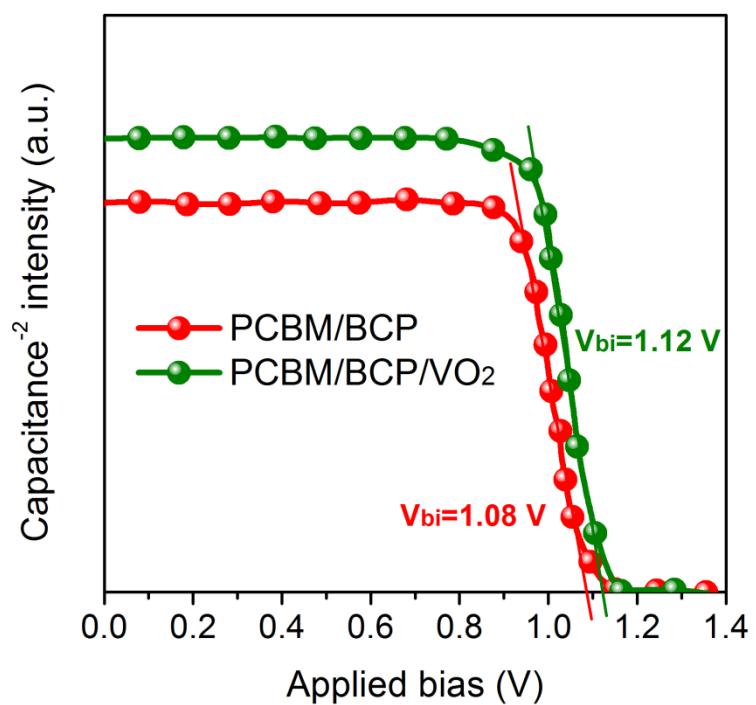
**Figure S13.** Nyquist plots of the EIS for the PSCs without and with VO<sub>2</sub> layer under dark condition at near open-circuit voltage.



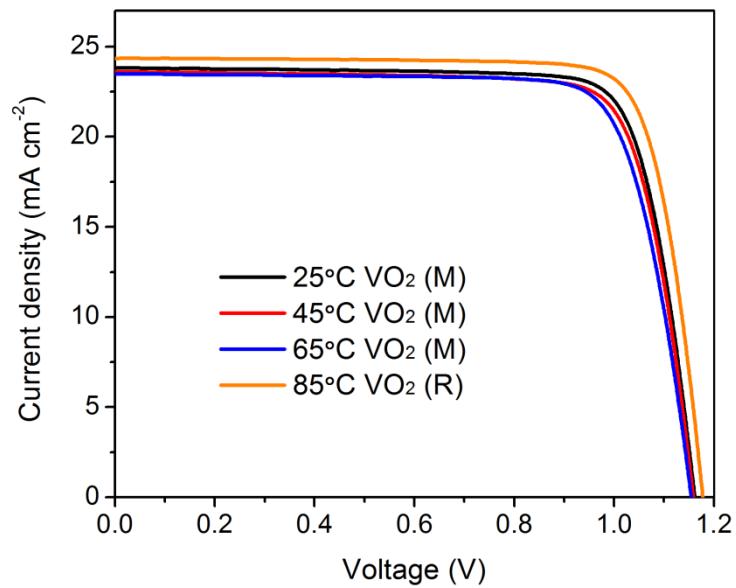
**Figure S14.** (a) Transient photocurrent (TPC) and (b) transient photovoltage (TPV) decay curves of PSCs.



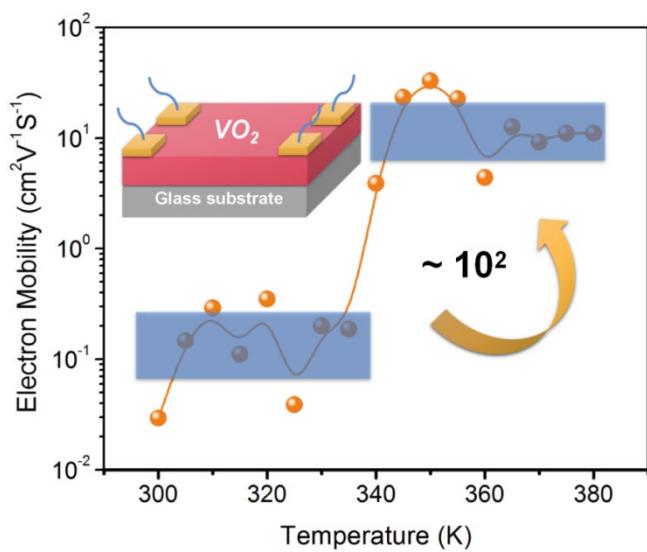
**Figure S15.** Light-intensity dependent (a)  $J_{sc}$  and (b)  $V_{oc}$  for the devices with or without  $\text{VO}_2$  layer, respectively.



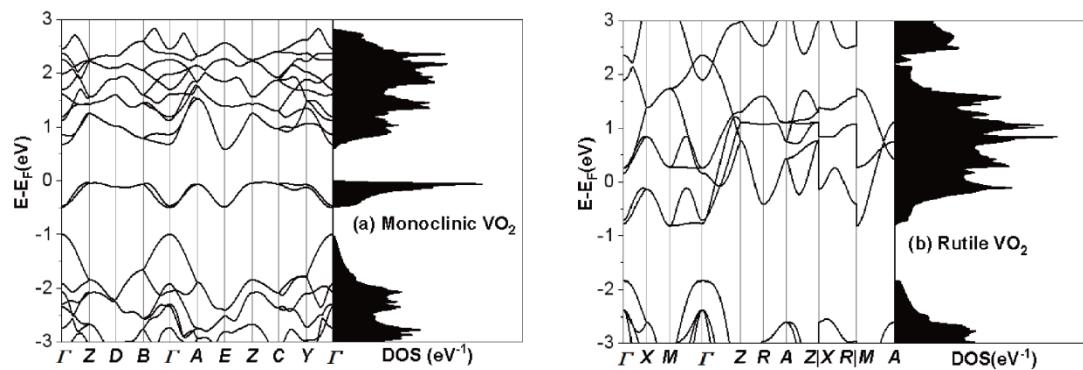
**Figure S16.** Mott-Schottky plots for the devices with and without VO<sub>2</sub> layer at 10 kHz.



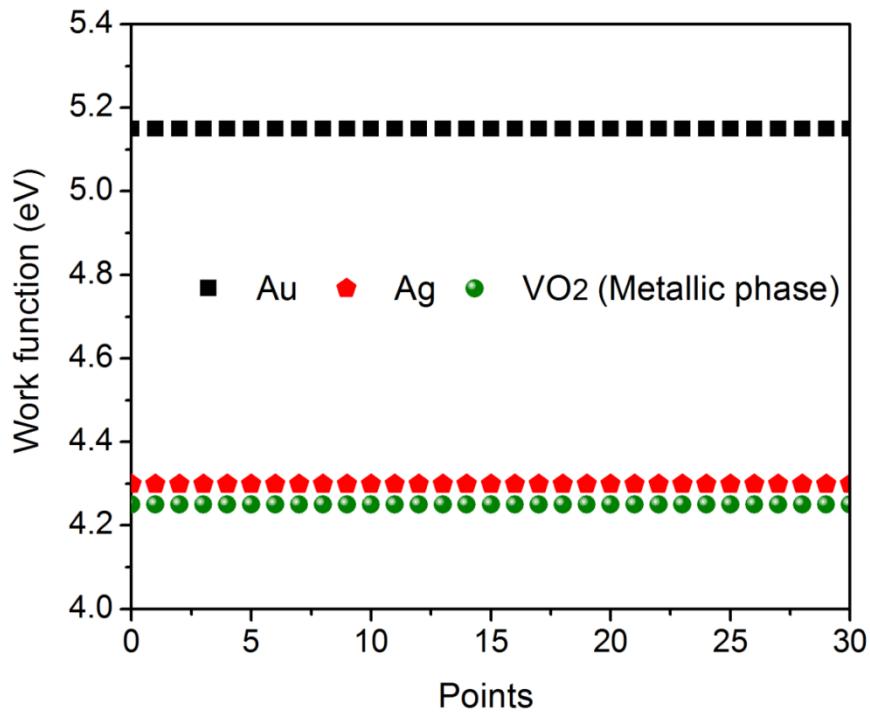
**Figure S17.** *J-V* curves of the VO<sub>2</sub>-based device measured at 25°C, 45°C, 65°C, and 85°C, respectively.



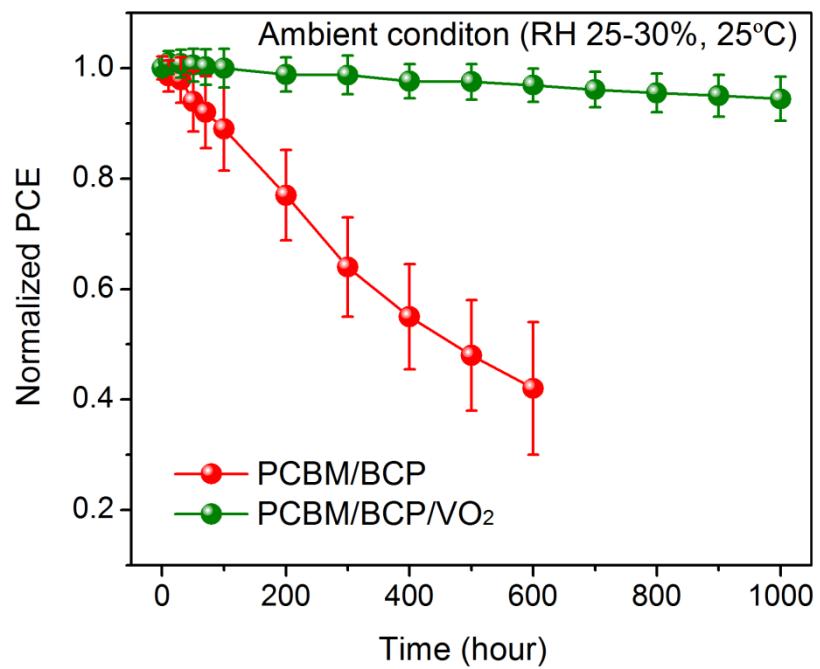
**Figure S18.** Temperature-dependent electron mobility of  $\text{VO}_2$  film.



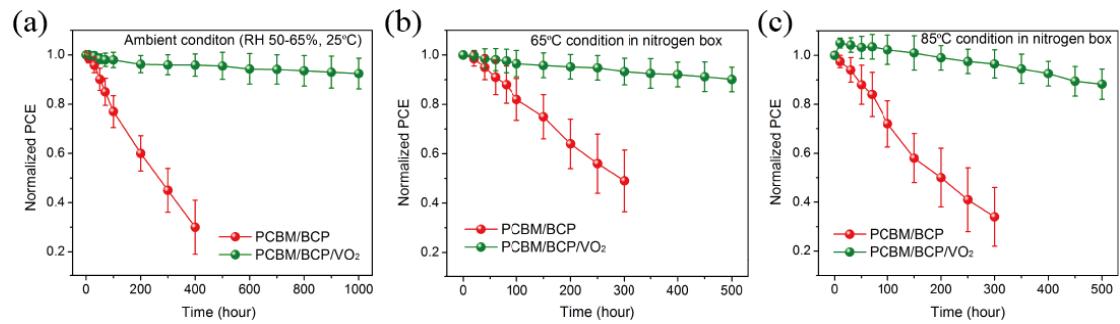
**Figure S19.** Band structures and density of states (DOS) of (a) Monoclinic  $\text{VO}_2$ , and (b) Rutile  $\text{VO}_2$ , respectively.



**Figure S20.** The work function of Au, Ag and VO<sub>2</sub> (metallic phase at 85°C). Before measuring, the WF of the tip was calibrated by a standard Au specimen with the WF of 5.15 eV.



**Figure S21.** Long term device stability evaluation of the PSCs without and with VO<sub>2</sub> in dry box environment (RH 25-30%, 25°C) in the dark condition.



**Figure S22.** (a) Long-term stability of the devices with and without VO<sub>2</sub> layer under ambient condition (RH 50-65%, 25°C). (b) Thermal stability of the devices with and without VO<sub>2</sub> layer under 65°C in nitrogen box without any encapsulation. (c) Thermal stability of the devices with and without VO<sub>2</sub> layer under 85°C in nitrogen box without any encapsulation.

**Table S1.** Summary of the photovoltaic parameters based on devices with different thicknesses of VO<sub>2</sub> layers forward scan (FS) and reverse scan (RS).

VO <sub>2</sub> Thickness	Scan Direction	V <sub>oc</sub> (V)	J <sub>sc</sub> (mA cm <sup>-2</sup> )	FF	PCE
<b>Control</b>	RS	1.14	23.15	79.43	20.96
	FS	1.14	23.22	78.57	20.80
<b>15 nm</b>	RS	1.15	23.50	79.54	21.49
	FS	1.15	23.52	79.20	21.42
<b>30 nm</b>	RS	1.16	23.82	80.03	22.11
	FS	1.16	23.83	79.71	22.03
<b>50 nm</b>	RS	1.14	22.68	79.43	20.53
	FS	1.14	22.75	78.57	20.37
<b>70 nm</b>	RS	1.13	22.13	78.01	19.50
	FS	1.13	22.14	77.80	19.46
<b>90 nm</b>	RS	1.10	21.29	76.60	17.93
	FS	1.10	21.32	76.03	17.83

**Table S2.** PL decay curves of perovskite films based on different ETLs well fitted by a bi-exponential decay kinetics equation:

$$PL = A_1 \exp(-t/\tau_1) + A_2 \exp(-t/\tau_2), \tau_{avg} = \tau_1 \times (A_1/A_1+A_2) + \tau_2 \times (A_2/A_1+A_2)$$

Sample name	$A_1$ (%)	$\tau_1$ (ns)	$A_2$ (%)	$\tau_2$ (ns)	$\tau_{avg}$
<b>Perovskite (Pero)</b>	12.9	7.6	87.1	179.9	157.6
<b>Pero/VO<sub>2</sub></b>	19.8	13.8	80.2	54.5	46.4
<b>Pero/PCBM</b>	34.3	11.7	65.7	44.0	32.9
<b>Pero/PCBM/VO<sub>2</sub></b>	12.3	5.3	87.7	28.2	25.4

**Table S3.** Summary of the photovoltaic performance of the reported high-efficiency PSCs with inverted configuration.

Device (Ref.)	$V_{oc}$ (V)	$J_{sc}$ (mA cm $^{-2}$ )	FF	PCE	Strategy
1	1.18	22.50	81.7	21.7	Additive engineering
2	1.21	22.50	79.0	21.5	N side engineering
3	1.21	22.49	78.5	21.4	Passivation engineering
4	1.12	23.05	80.3	20.7	P side engineering
5	1.13	23.30	80.0	21.1	Additive engineering
6	1.14	23.70	78.0	21.0	Passivation engineering
7	1.15	22.69	78.5	20.4	Additive engineering
8	1.13	22.40	80.0	20.3	Additive engineering
9	1.09	23.60	78.6	20.2	Novel HTL materials
10	1.12	23.23	81.4	21.2	Novel HTL materials
11	1.20	22.58	81.3	22.0	Novel ETL materials
12	1.14	23.68	81.0	21.9	Single-Crystal PSC
13	1.21	22.59	81.6	22.3	Interface engineering
14	1.17	24.10	81.6	23.0	Additive engineering
15	1.17	24.92	80.2	23.4	Interface engineering
<b>This work</b>	<b>1.18</b>	<b>24.38</b>	<b>81.0</b>	<b>23.1</b>	<b>Interface modification</b>

**Table S4.** Summary of the photovoltaic parameters for VO<sub>2</sub>-based PSC measured at 25°C, 45°C, 65°C, and 85°C, respectively.

Temperature (°C)	V <sub>oc</sub> (V)	J <sub>sc</sub> (mA cm <sup>-2</sup> )	FF	PCE
25	1.164	23.82	80.03	22.11
45	1.159	23.63	79.38	21.73
65	1.154	23.45	78.74	21.30
85	1.178	24.38	81.03	23.11

**Table S5.** Lattice parameters of VO<sub>2</sub> crystal phases.

	a (Å)	b (Å)	c (Å)	α (°)	β (°)	γ (°)	
VO <sub>2</sub> (M)	5.398	4.500	5.390	90	115.330	90	Exp.
	5.335	4.529	5.357	90	116.483	90	Cal.
VO <sub>2</sub> (R)	4.542	4.542	2.872	90	90	90	Exp.
	4.563	4.563	2.775	90	90	90	Cal.

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